



FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE
INFORMATION DISCLOSURE CITATION**

(Use several sheets if necessary)

Sheet 1 of 1

ATTORNEY DOCKET NO.

3197-000058

SERIAL NO.

10/727,081

APPLICANT

David Coumou et al.

FILING DATE

December 2, 2003

GROUP

2858

U.S. PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	US	6,449,568	9/10/02	Gerrish		

FOREIGN PATENT DOCUMENTS

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	US	EP 1 339 086 A2	8/27/03	Europe		X	

OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)

Ref. Desig.	Examiner's Initials	
1.	US	Advanced RF Metrology for Plasma Process Control, David Coumou, October 2003.

Examiner:

C. M. Z.

Date Considered:

7/6/05

EXAMINER: Please initial if citation considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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1.	JS	6,449,568	9/10/02	Gerrish		
2.		5,867,020	2/2/99	Moore et al.		
3.		5,834,931	11/10/98	Moore et al.		

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